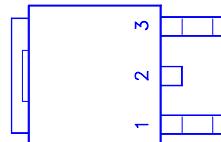
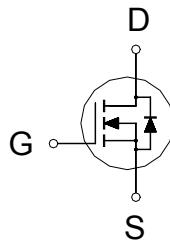


**NIKO-SEM**
**N-Channel Logic Level Enhancement  
Mode Field Effect Transistor**
**P75N02LD**  
**TO-252 (D<sup>2</sup>PAK)**
**PRODUCT SUMMARY**

| $V_{(BR)DSS}$ | $R_{DS(ON)}$ | $I_D$ |
|---------------|--------------|-------|
| 25            | 5mΩ          | 75A   |


 1. GATE  
 2. DRAIN  
 3. SOURCE
**ABSOLUTE MAXIMUM RATINGS ( $T_C = 25^\circ\text{C}$  Unless Otherwise Noted)**

| PARAMETERS/TEST CONDITIONS                         |                           | SYMBOL         | LIMITS     | UNITS |
|--|---------------------------|----------------|------------|-------|
| Gate-Source Voltage                                |                           | $V_{GS}$       | $\pm 20$   | V     |
| Continuous Drain Current                           | $T_C = 25^\circ\text{C}$  | $I_D$          | 75         | A     |
|  | $T_C = 100^\circ\text{C}$ |                | 50         |       |
| Pulsed Drain Current <sup>1</sup>                  |                           | $I_{DM}$       | 170        |       |
| Avalanche Current                                  |                           | $I_{AR}$       | 60         |       |
| Avalanche Energy                                   | $L = 0.1\text{mH}$        | $E_{AS}$       | 140        | mJ    |
| Repetitive Avalanche Energy <sup>2</sup>           | $L = 0.05\text{mH}$       | $E_{AR}$       | 5.6        |       |
| Power Dissipation                                  | $T_C = 25^\circ\text{C}$  | $P_D$          | 65         | W     |
|  | $T_C = 100^\circ\text{C}$ |                | 38         |       |
| Operating Junction & Storage Temperature Range     |                           | $T_j, T_{stg}$ | -55 to 150 | °C    |
| Lead Temperature ( $1/16$ " from case for 10 sec.) |                           | $T_L$          | 275        |       |

**THERMAL RESISTANCE RATINGS**

| THERMAL RESISTANCE  | SYMBOL          | TYPICAL | MAXIMUM | UNITS  |
|---------------------|-----------------|---------|---------|--------|
| Junction-to-Case    | $R_{\theta JC}$ |         | 2.3     | °C / W |
| Junction-to-Ambient | $R_{\theta JA}$ |         | 62.5    |        |
| Case-to-Heatsink    | $R_{\theta CS}$ |         | 0.6     |        |

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>Duty cycle ≤ 1%**ELECTRICAL CHARACTERISTICS ( $T_C = 25^\circ\text{C}$ , Unless Otherwise Noted)**

| PARAMETER                       | SYMBOL        | TEST CONDITIONS  | LIMITS |     |           | UNIT          |
|---------------------------------|---------------|--|--------|-----|-----------|---------------|
|                                 |               |  | MIN    | TYP | MAX       |               |
| <b>STATIC</b>                   |               |  |        |     |           |               |
| Drain-Source Breakdown Voltage  | $V_{(BR)DSS}$ | $V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$                         | 25     |     |           | V             |
| Gate Threshold Voltage          | $V_{GS(th)}$  | $V_{DS} = V_{GS}, I_D = 250\mu\text{A}$                            | 1      | 1.5 | 3         |               |
| Gate-Body Leakage               | $I_{GSS}$     | $V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$                      |        |     | $\pm 250$ | nA            |
| Zero Gate Voltage Drain Current | $I_{DSS}$     | $V_{DS} = 20\text{V}, V_{GS} = 0\text{V}$                          |        |     | 25        | $\mu\text{A}$ |
|                                 |               | $V_{DS} = 20\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$ |        |     | 250       |               |

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|   |                      |   |    |       |     |    |
|---|----------------------|---|----|-------|-----|----|
| On-State Drain Current <sup>1</sup>   | I <sub>D(ON)</sub>   | V <sub>DS</sub> = 10V, V <sub>GS</sub> = 10V  | 70 |       |     | A  |
| Drain-Source On-State Resistance <sup>1</sup>                                 | R <sub>DS(ON)</sub>  | V <sub>GS</sub> = 10V, I <sub>D</sub> = 30A   |    | 5     | 7   | mΩ |
|   |                      | V <sub>GS</sub> = 7V, I <sub>D</sub> = 24A  |    | 6     | 8   |    |
| Forward Transconductance <sup>1</sup>   | g <sub>f</sub>       | V <sub>DS</sub> = 15V, I <sub>D</sub> = 30A   |    | 16    |     | S  |
| <b>DYNAMIC</b>  |                      |   |    |       |     |    |
| Input Capacitance   | C <sub>iss</sub>     | V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1MHz   |    | 5000  |     | pF |
| Output Capacitance  | C <sub>oss</sub>     |   |    | 1800  |     |    |
| Reverse Transfer Capacitance  | C <sub>rss</sub>     |   |    | 800   |     |    |
| Total Gate Charge <sup>2</sup>  | Q <sub>g</sub>       | V <sub>DS</sub> = 0.5V <sub>(BR)DSS</sub> , V <sub>GS</sub> = 10V,<br>I <sub>D</sub> = 35A                        |    | 140   |     | nC |
| Gate-Source Charge <sup>2</sup>   | Q <sub>gs</sub>      |   |    | 40    |     |    |
| Gate-Drain Charge <sup>2</sup>  | Q <sub>gd</sub>      |   |    | 75    |     |    |
| Turn-On Delay Time <sup>2</sup>   | t <sub>d(on)</sub>   | V <sub>DS</sub> = 15V, R <sub>L</sub> = 1Ω<br>I <sub>D</sub> ≈ 30A, V <sub>GS</sub> = 10V, R <sub>GS</sub> = 2.5Ω |    | 7     |     | nS |
| Rise Time <sup>2</sup>  | t <sub>r</sub>       |   |    | 7     |     |    |
| Turn-Off Delay Time <sup>2</sup>  | t <sub>d(off)</sub>  |   |    | 24    |     |    |
| Fall Time <sup>2</sup>  | t <sub>f</sub>       |   |    | 6     |     |    |
| <b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T<sub>C</sub> = 25 °C)</b> |                      |   |    |       |     |    |
| Continuous Current  | I <sub>S</sub>       | I <sub>F</sub> = I <sub>S</sub> , V <sub>GS</sub> = 0V  |    |       | 75  | A  |
| Pulsed Current <sup>3</sup>   | I <sub>SM</sub>      |   |    |       | 170 |    |
| Forward Voltage <sup>1</sup>  | V <sub>SD</sub>      | I <sub>F</sub> = I <sub>S</sub> , dI <sub>F</sub> /dt = 100A / μS   |    |       | 1.3 | V  |
| Reverse Recovery Time   | t <sub>rr</sub>      |   |    | 37    |     | nS |
| Peak Reverse Recovery Current   | I <sub>RM(REC)</sub> |   |    | 200   |     | A  |
| Reverse Recovery Charge   | Q <sub>rr</sub>      |   |    | 0.043 |     | μC |

<sup>1</sup>Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.<sup>2</sup>Independent of operating temperature.<sup>3</sup>Pulse width limited by maximum junction temperature.**REMARK: THE PRODUCT MARKED WITH “P75N02LD”, DATE CODE or LOT #**

**NIKO-SEM****N-Channel Logic Level Enhancement  
Mode Field Effect Transistor****P75N02LD  
TO-252 (D<sup>2</sup>PAK)****TO-252 (DPAK) MECHANICAL DATA**

| Dimension | mm   |      |      | Dimension | mm   |      |      |
|-----------|------|------|------|-----------|------|------|------|
|           | Min. | Typ. | Max. |           | Min. | Typ. | Max. |
| A         | 9.35 |      | 10.1 | H         |      | 0.8  |      |
| B         | 2.2  |      | 2.4  | I         | 6.4  |      | 6.6  |
| C         | 0.48 |      | 0.6  | J         | 5.2  |      | 5.4  |
| D         | 0.89 |      | 1.5  | K         | 0.6  |      | 1    |
| E         | 0.45 |      | 0.6  | L         | 0.64 |      | 0.9  |
| F         | 0.03 |      | 0.23 | M         | 4.4  |      | 4.6  |
| G         | 6    |      | 6.2  | N         |      |      |      |

